



- Plug-in replacement for Static RAM chips
- Retains data for up to 10 years
- No erasure required
- Functions as Data or Program RAM
- No limit to number of programming cycles
- Fits standard 24-pin socket

NVR2 is a 2 kilobyte non-volatile memory module which is pin-compatible with normal Static RAM chips, and offers immediate conversion to non-volatile memory of all or part of a system, able to retain data and survive power-downs for up to 10 years.

REPLACES: 2016 6116 8416 5517 4016
2128 5128 PD446 8128 4802
5116 etc.

MAXIMUM RATINGS

Symbol	Min	Max	Unit
V_{dd}	-0.3	7.0	Volts
$V_{i/o}$	-0.3	$V_{dd} + 0.3$	Volts
Temp.	-10	+70	deg. C

OPERATING CONDITIONS

Symbol	Min	Typ	Max	Unit
V_{dd}	4.5	5.0	5.5	V
$V_{in}(1)$	2.2		$V_{dd} + 3$	V
$V_{in}(0)$	-0.3		0.8	V
$I_{in}(\text{any pin})^*$	-1		+1	uA
$V_{out}(1) (I_{out} = -1\text{mA})$	2.4			V
$V_{out}(0) (I_{out} = -2\text{mA})$			0.4	V
$I_{dd}(\text{Active})$		25		mA
$I_{dd}(\text{Standby})$		5		uA
T_{cycle}			200	nS
$C_{in}(\text{any pin})$		7		pF

*INH: 4 70 kohm pull-up to V_{dd}

FUNCTION MODE

INH	CE	OE	WR	MODE	OUTPUT	I_{dd}
X	H	X	X	Unsel.	Hi-Z	Standby
X	L	H	H	Unsel.	Hi-Z	Active
X	L	L	H	Read	D_{out}	Active
H	L	X	L	Write	D_{in}	Active
L	L	X	L	WRITE INHIBIT		Active

2K x 8 NON-VOLATILE RAM NVR2

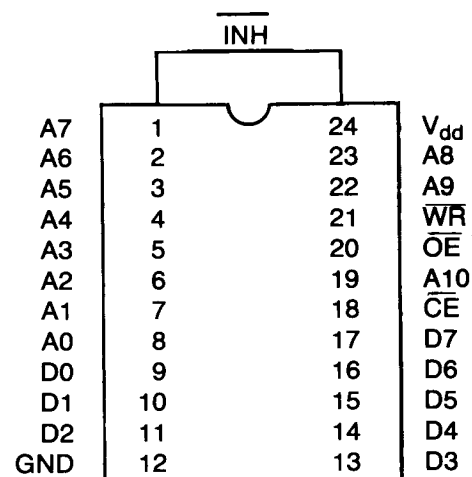


Dimensions	mm
Length	32.5
Width	18
Height	7.3

PIN DESIGNATIONS

Pin	Function
A0-A10	Address I/Ps
D0-D7	Data in/out
\overline{OE}	Output Enable
\overline{CE}	Chip Enable
\overline{WR}	Write Input
V_{dd}	+5V power
GND	Ground
\overline{INH}	Extra I/P

PIN CONNECTIONS



REPRESENTATIVE/IMPORTER

3401 MONROE RD. • CHARLOTTE, NC 28205
(704) 376-7805, TELEX: 358-905

TIMING DIAGRAMS (units — nano-seconds)

READ CYCLE

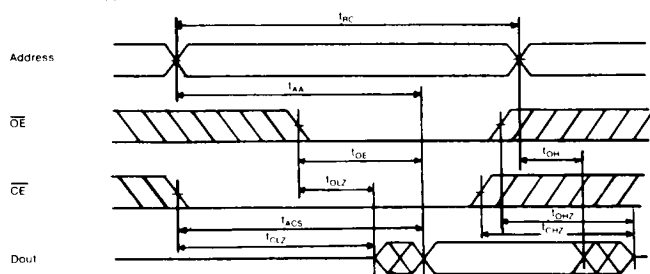
Characteristic	Label	Min	Max
Read cycle time	T_{rc}	200	
Address to O/P valid	T_{aa}		200
\overline{CE} to O/P valid	T_{acs}		200
\overline{OE} to O/P valid	T_{oe}		100
Output hold time	T_{oh}	20	
\overline{CE} to O/P enable	T_{clz}	10	
\overline{OE} to O/P enable	T_{olz}	10	
\overline{CE} to O/P disable	T_{chz}	100	
\overline{OE} to O/P disable	T_{ohz}	100	

(EOW = End of Write)

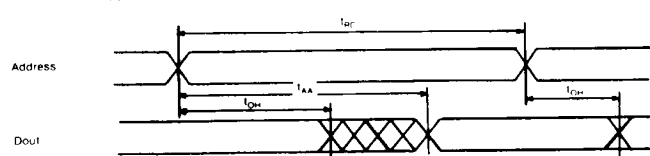
WRITE CYCLE

Characteristic	Label	Min	Max
Write cycle time	T_{wc}	200	
\overline{CE} to EOW	T_{cw}	170	
Addr valid to EOW	T_{aw}	170	
Addr set-up time	T_{as}	0	
Write pulse width	T_{wp}	170	
\overline{WR} recovery time	T_{wr}	0	
Data valid to EOW	T_{dw}	100	
Data hold time	T_{dh}	0	
\overline{WR} to O/P disable	T_{whz}		100
\overline{OE} from EOW	T_{ow}	20	
\overline{OE} to O/P disable	T_{ohz}	0	

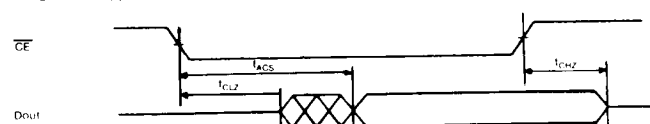
• READ CYCLE (1) Notes 1, 5



• READ CYCLE (2) Notes 1, 2, 4, 5

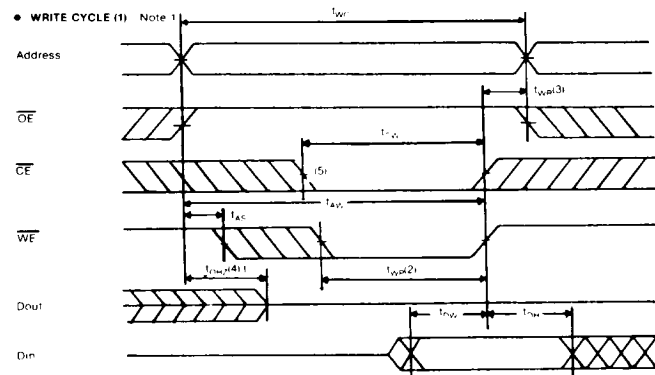


• READ CYCLE (3) Notes 1, 3, 4, 5

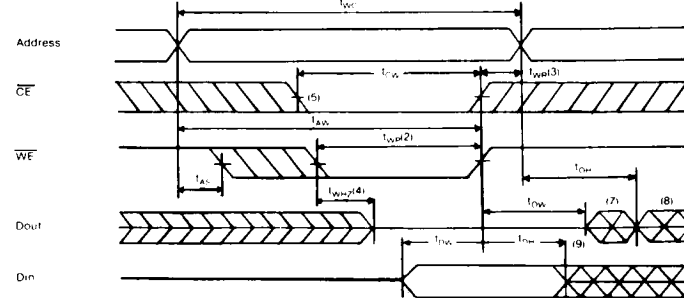


NOTES — READ CYCLE

1. \overline{WE} is high for read cycle.
2. Device is continuously selected, $\overline{CE} = V_{il}$.
3. Address valid prior to or coincident with \overline{CE} transition low.
4. $\overline{OE} = V_{il}$.
5. When \overline{CE} is low, address inputs must not be in the high impedance state.



• WRITE CYCLE (2) Notes 1, 6



NOTES — WRITE CYCLE

1. \overline{WE} must be high during address transitions.
2. A Write occurs during the overlap of a low \overline{CE} and a low \overline{WE} .
3. T_{wr} measured from the earlier of \overline{CE} or \overline{WE} going high to end of write cycle.
4. During this period, I/O pins are in the O/P state.
5. If a \overline{CE} low transition occurs simultaneously with or after a \overline{WE} transition, O/Ps remain in a high impedance state.
6. \overline{OE} is continuously low ($\overline{OE} = V_{il}$).
7. D_{out} is the same phase of write data of this write cycle.
8. D_{out} is the read data of next address.
9. If \overline{CE} is low during this period, I/O pins are in the output state.